

# PH3230

N-channel enhancement mode field-effect transistor

Rev. 02 — 5 September 2002

Product data

## 1. Description

The latest generation N-channel enhancement mode field-effect power transistor in a SOT669 (LPAK) package.

Product availability:

PH3230 in SOT669 (LPAK).

## 2. Features

- Logic level compatible
- Low drive current
- High density mounting
- Very low on-state resistance.

## 3. Applications

- DC to DC converter
- Computer motherboards
- Switch mode power supplies.

## 4. Pinning information

Table 1: Pinning - SOT669 (LPAK), simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1,2,3	source (s)	<p>Top view MBL286</p> <p><b>SOT669 (LPAK)</b></p>	<p>MBL288</p>
4	gate (g)		
mb	mounting base, connected to drain (d)		

## 5. Quick reference data

**Table 2: Quick reference data**

Symbol	Parameter	Conditions	Typ	Max	Unit
$V_{DS}$	drain-source voltage (DC)	$T_j = 25\text{ °C}$	-	30	V
$I_D$	drain current (DC)	$T_{mb} = 25\text{ °C}$	-	50	A
$P_{tot}$	total power dissipation	$T_{mb} = 25\text{ °C}$	-	42	W
$T_j$	junction temperature		-	150	°C
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 25\text{ A}; T_j = 25\text{ °C}$	3.2	3.7	mΩ
		$V_{GS} = 4.5\text{ V}; I_D = 25\text{ A}; T_j = 25\text{ °C}$	5.5	7.3	mΩ

## 6. Limiting values

**Table 3: Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

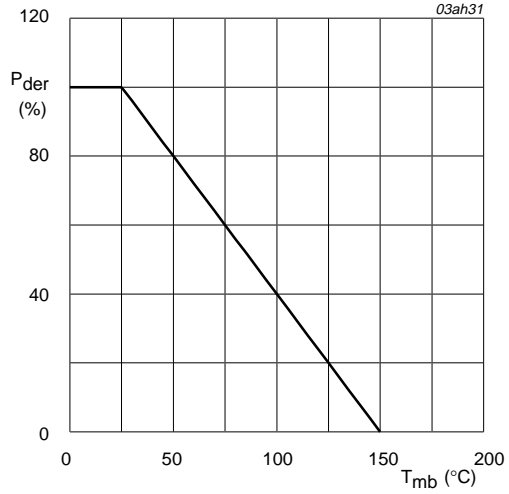
Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage (DC)	$25\text{ °C} \leq T_j \leq 150\text{ °C}$	-	30	V
$V_{GS}$	gate-source voltage (DC)		-	±20	V
$I_D$	drain current (DC)	$V_{GS} = 10\text{ V}; T_{mb} = 25\text{ °C};$ <a href="#">Figure 2</a> and <a href="#">5</a>	-	50	A
$I_{DM}$	peak drain current	$T_{mb} = 25\text{ °C};$ pulsed; $t_p \leq 10\text{ }\mu\text{s};$ <a href="#">Figure 5</a>	-	200	A
$P_{tot}$	total power dissipation	$T_{mb} = 25\text{ °C};$ <a href="#">Figure 1</a>	-	42	W
$T_{stg}$	storage temperature		-55	+150	°C
$T_j$	junction temperature		-55	+150	°C

### Source-drain diode

$I_{SM}$	peak source (diode forward) current	$T_{mb} = 25\text{ °C};$ pulsed; $t_p \leq 10\text{ }\mu\text{s}$	-	50	A
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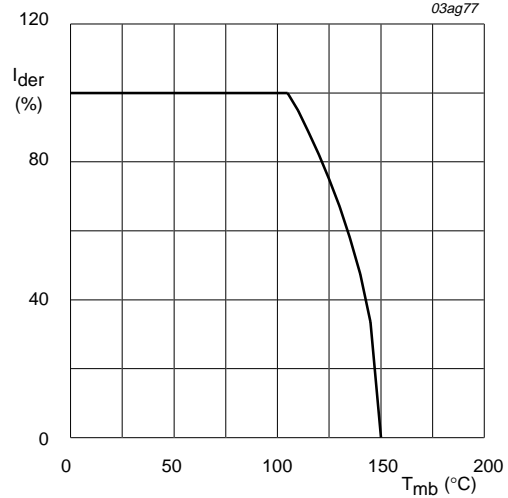
### Avalanche ruggedness

$I_{DS(AL)R}$	repetitive drain-source avalanche current	$T_j = 25\text{ °C}$	-	5	A
$E_{DS(AL)R}$	repetitive drain-source avalanche energy	$T_j = 25\text{ °C}; R_{GS} \geq 50\text{ }\Omega; I_{DS(AL)R} = 5\text{ A}; V_{DD} = 15\text{ V};$ duty < 0.1%	-	2.5	mJ



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

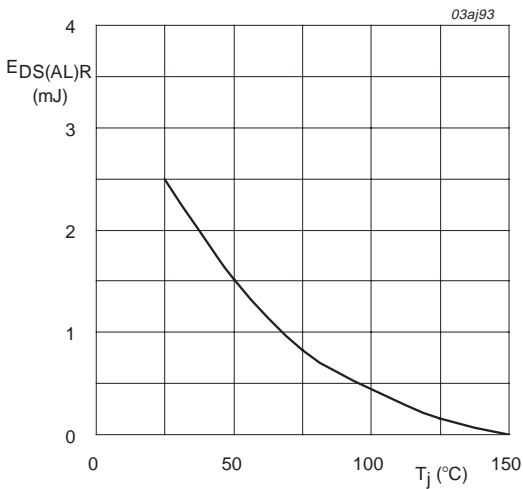
Fig 1. Normalized total power dissipation as a function of mounting base temperature.



V<sub>GS</sub> ≥ 10 V

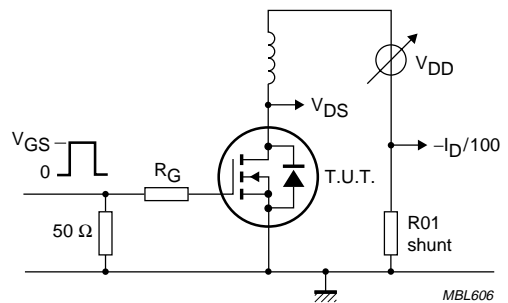
$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature.



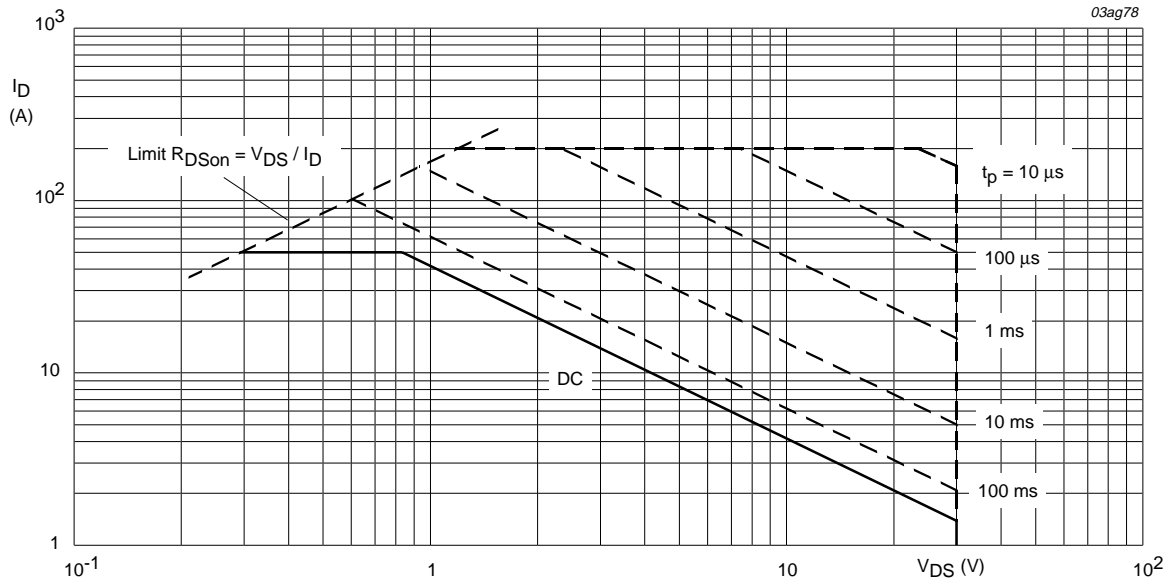
I<sub>AR</sub> = 5 A; V<sub>DD</sub> = 15V; duty < 0.1%; R<sub>G</sub> ≥ 50Ω

Fig 3. Repetitive avalanche energy rating.



$$E_{AR} = 0.5 \times (LI_{AR})^2 \times \frac{V_{DSS}}{V_{DSS} - V_{DD}}$$

Fig 4. Avalanche energy test circuit.



$T_{mb} = 25 \text{ }^\circ\text{C}$ ;  $I_{DM}$  is single pulse.

Fig 5. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

## 7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Figure 6	-	-	3	K/W

### 7.1 Transient thermal impedance

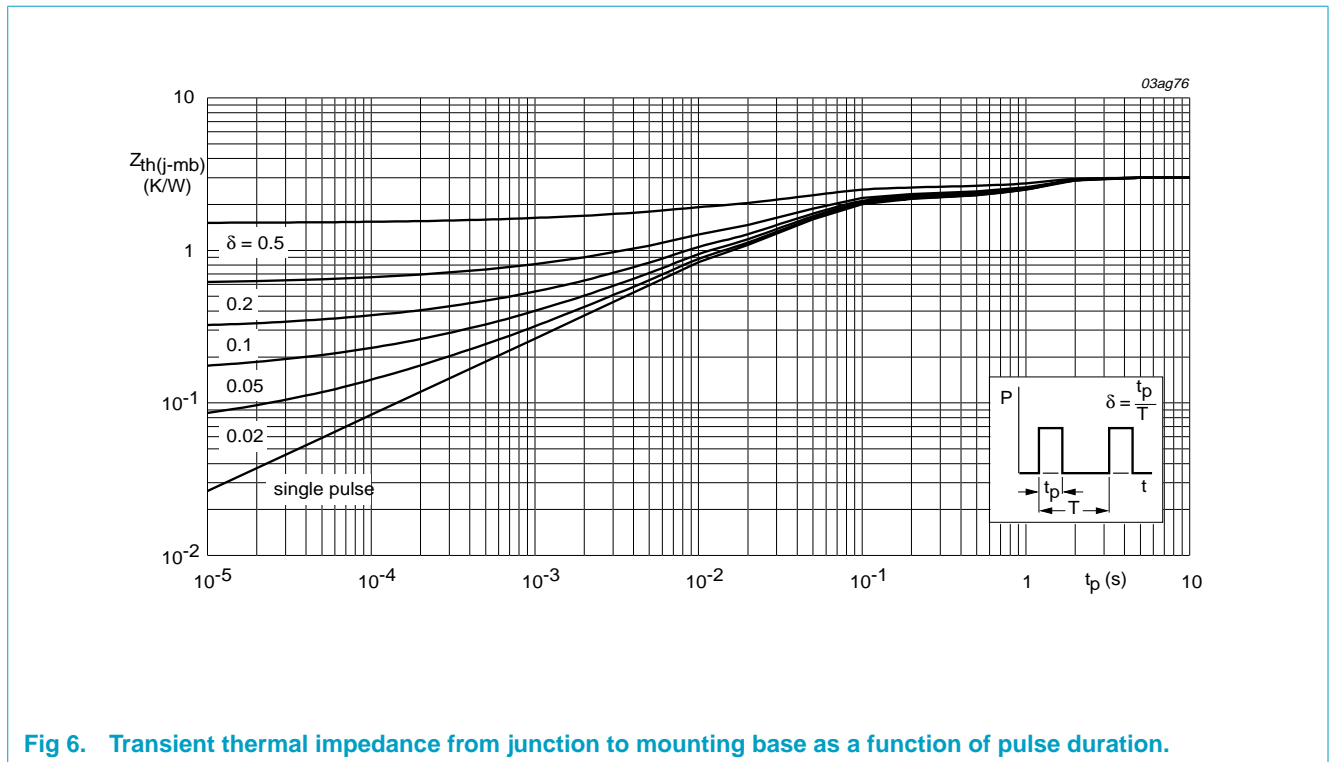


Fig 6. Transient thermal impedance from junction to mounting base as a function of pulse duration.

## 8. Characteristics

**Table 5: Characteristics**

$T_j = 25\text{ }^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static characteristics</b>						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10\text{ mA}; V_{GS} = 0\text{ V}$	30	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1\text{ mA}; V_{DS} = V_{GS}$ ; <b>Figure 11</b>	1	1.9	2.5	V
$I_{DSS}$	drain-source leakage current	$V_{DS} = 30\text{ V}; V_{GS} = 0\text{ V}$	-	-	1	$\mu\text{A}$
$I_{GSS}$	gate-source leakage current	$V_{GS} = \pm 16\text{ V}; V_{DS} = 0\text{ V}$	-	0.1	10	$\mu\text{A}$
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 25\text{ A}$ ; <b>Figure 9 and 10</b>	-	3.2	3.7	$\text{m}\Omega$
		$V_{GS} = 4.5\text{ V}; I_D = 25\text{ A}$ ; <b>Figure 10</b>	-	5.5	7.3	$\text{m}\Omega$
<b>Dynamic characteristics</b>						
$g_{fs}$	forward transconductance	$V_{DS} = 10\text{ V}; I_D = 25\text{ A}$ ; <b>Figure 13</b>	39	55	-	S
$Q_{g(tot)}$	total gate charge	$I_D = 50\text{ A}; V_{DD} = 10\text{ V}; V_{GS} = 10\text{ V}$ ; <b>Figure 16</b>	-	75	-	nC
$Q_{gs}$	gate-source charge		-	16	-	nC
$Q_{gd}$	gate-drain (Miller) charge		-	14	-	nC
$C_{iss}$	input capacitance	$V_{GS} = 0\text{ V}; V_{DS} = 10\text{ V}; f = 1\text{ MHz}$ ; <b>Figure 14</b>	-	4750	-	pF
$C_{oss}$	output capacitance		-	1160	-	pF
$C_{rss}$	reverse transfer capacitance		-	630	-	pF
$t_{d(on)}$	turn-on delay time	$V_{DD} = 10\text{ V}; I_D = 25\text{ A}; V_{GS} = 10\text{ V}; R_G = 4.7\ \Omega$	-	25	-	ns
$t_r$	rise time		-	50	-	ns
$t_{d(off)}$	turn-off delay time		-	90	-	ns
$t_f$	fall time		-	26	-	ns
<b>Source-drain (reverse) diode</b>						
$V_{SD}$	source-drain (diode forward) voltage	$I_S = 50\text{ A}; V_{GS} = 0\text{ V}$ ; <b>Figure 15</b>	-	0.85	0.98	V
$t_{rr}$	reverse recovery time	$I_S = 50\text{ A}; dI_S/dt = -50\text{ A}/\mu\text{s}; V_{GS} = 0\text{ V}$	-	60	-	ns

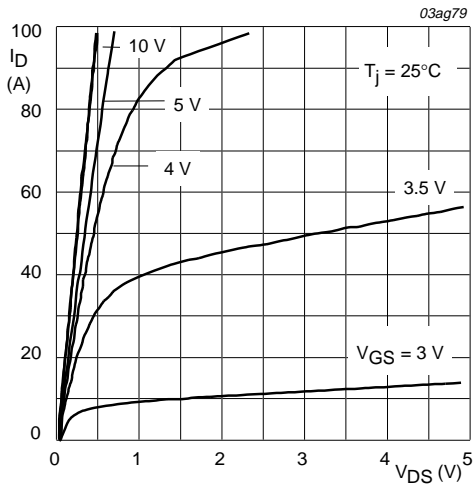


Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values.

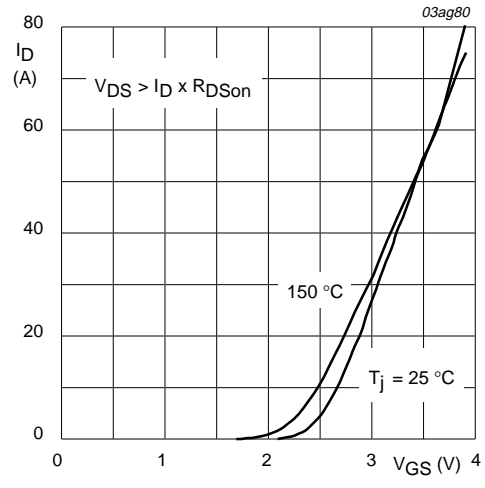


Fig 8. Transfer characteristics: drain current as a function of gate-source voltage; typical values.

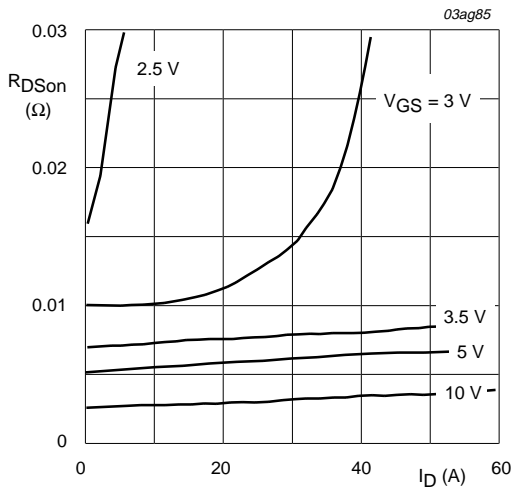
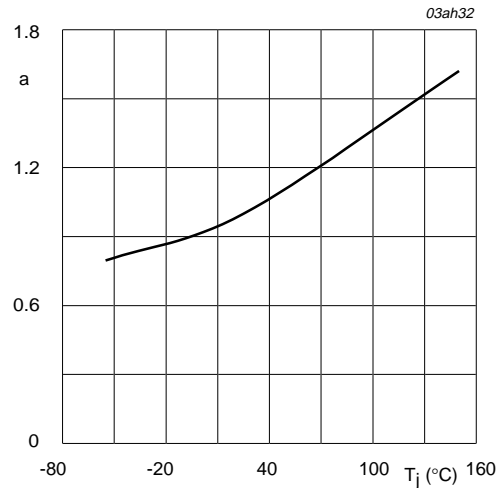
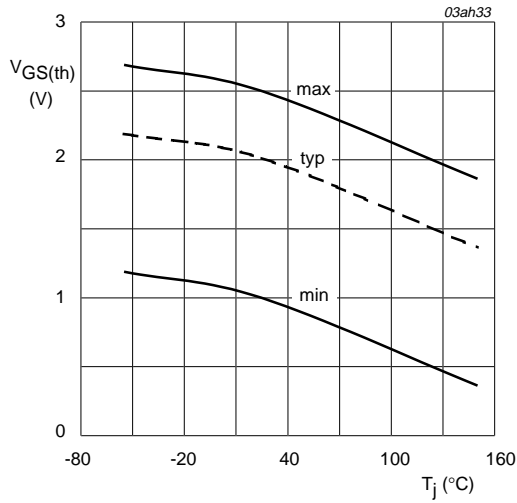


Fig 9. Drain-source on-state resistance as a function of drain current; typical values.



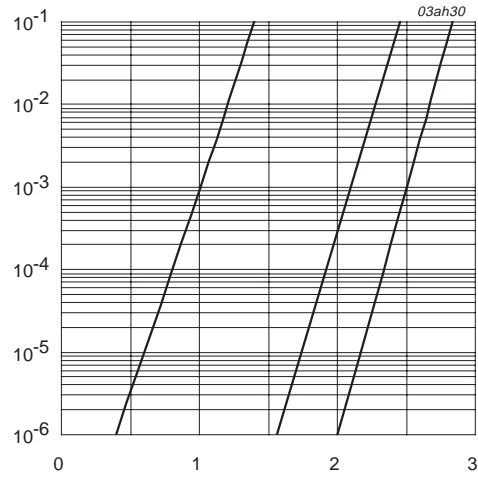
$$a = \frac{R_{DSon}}{R_{DSon(25^\circ\text{C})}}$$

Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature.



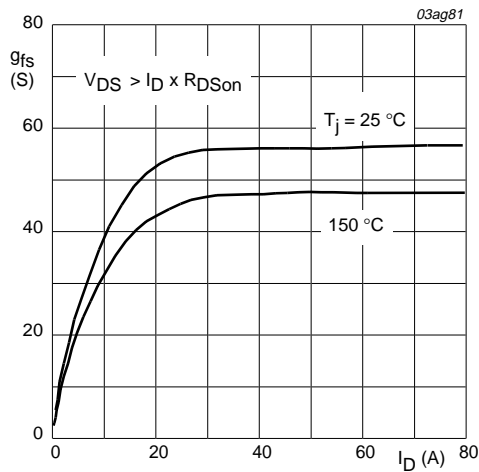
$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 11. Gate-source threshold voltage as a function of junction temperature



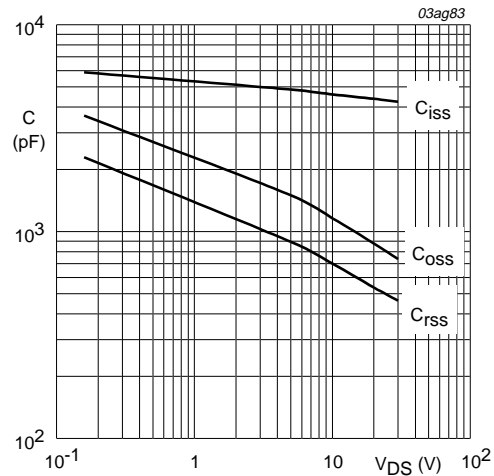
$T_j = 25 \text{ }^{\circ}C$

Fig 12. Sub-threshold drain current as a function of gate-source voltage.



$T_j = 25 \text{ }^{\circ}C$  and  $150 \text{ }^{\circ}C; V_{DS} > I_D \times R_{DSon}$

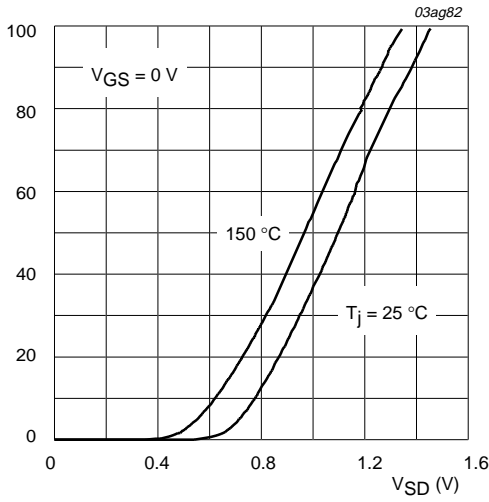
Fig 13. Forward transconductance as a function of drain current; typical values.



$V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

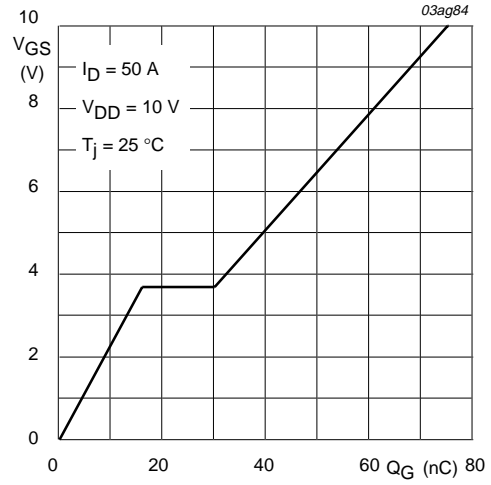
Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.





$T_j = 25\text{ °C}$  and  $150\text{ °C}$ ;  $V_{GS} = 0\text{ V}$

**Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.**



$T_j = 25\text{ °C}$ ;  $I_D = 50\text{ A}$ ;  $V_{DD} = 10\text{ V}$

**Fig 16. Gate-source voltage as a function of gate charge; typical values.**

9. Package outline

Plastic single-ended surface mounted package (Philips version LPAK); 4 leads

SOT669

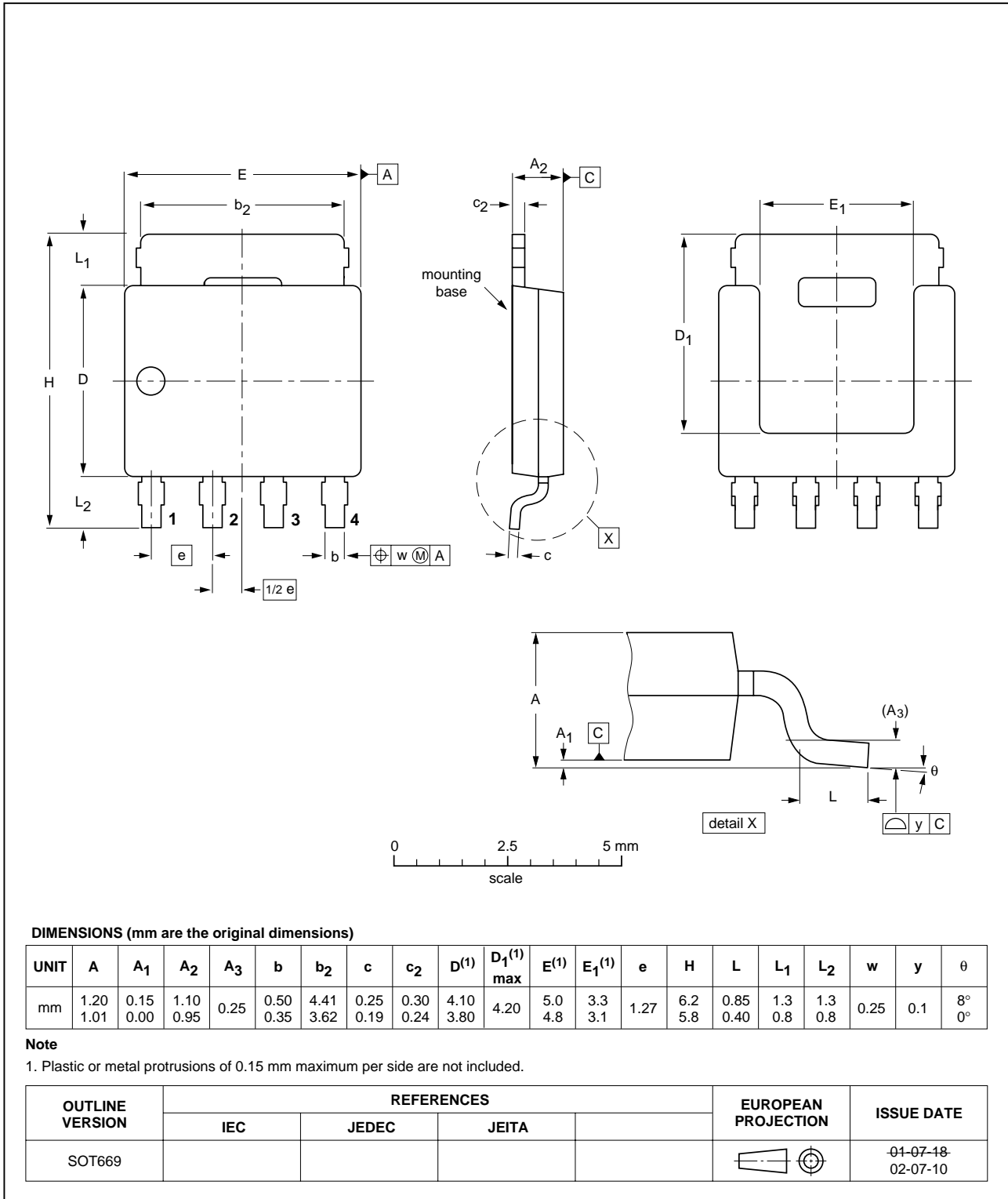


Fig 17. SOT669 (LPAK).

## 10. Revision history

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Table 6: Revision history

Rev	Date	CPCN	Description
02	20020905		<b>Product data (9397 750 10122)</b> Modifications: <ul style="list-style-type: none"><li>• Ruggedness graphs and data added.</li></ul>
01	20020207		<b>Product data (9397 750 09395)</b>

## 11. Data sheet status

Data sheet status <sup>[1]</sup>	Product status <sup>[2]</sup>	Definition
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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[1] Please consult the most recently issued data sheet before initiating or completing a design.

[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL <http://www.semiconductors.philips.com>.

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**Limiting values definition** — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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## Contents

1	Description . . . . .	1
2	Features . . . . .	1
3	Applications . . . . .	1
4	Pinning information . . . . .	1
5	Quick reference data . . . . .	2
6	Limiting values . . . . .	2
7	Thermal characteristics . . . . .	5
7.1	Transient thermal impedance . . . . .	5
8	Characteristics . . . . .	6
9	Package outline . . . . .	10
10	Revision history . . . . .	11
11	Data sheet status . . . . .	12
12	Definitions . . . . .	12
13	Disclaimers . . . . .	12

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